Over the course of a year, those who write about test for the trade press get to talk to industry leaders about topics ranging from ATE to DFT. At ITC, while most attendees are in sessions or on the floor, the press is talking to a wide range of test companies and executives.

During these interviews they ask about major trends in test. In this panel, we will turn the tables and have the Test Press tell us their opinions, based on their extensive knowledge of the industry.

Some of the topics we will be covering are:
- What do they think is the biggest test problem we face today?
- What are we doing right, and what are we doing wrong?
- What will the ATE of the future look like?
- Will we be able to afford it?
- Will anyone make lots of money in test?

The audience will have a chance to ask questions, and then the Press will really Strike Back by surveying the audience to get our opinions on some critical test issues.

Moderator: Scott Davidson, Sun Microsystems, Inc.

Panelists:
- Jim Mulady, Final Test Report
- Rick Nelson, Test & Measurement World
- Mike Riezenman, IEEE Spectrum
- Dan Strassberg, EDN